

2.5V / 3.3V PHASE-LOCK LOOP CLOCK DRIVER ZERO DELAY BUFFER

IDT5V2528/A

PRODUCT DISCONTINUATION NOTICE - LAST TIME BUY EXPIRES OCTOBER 28, 2014

FEATURES:

- Operates at 3.3V VDD/AVDD and 2.5V/3.3V VDDQ
- 1:10 fanout
- · 3-level inputs for output control
- External feedback (FBIN) pin is used to synchronize the outputs to the clock input signal
- No external RC network required for PLL loop stability
- · Configurable 2.5V or 3.3V LVTTL outputs
- tpd Phase Error at 100MHz to 166MHz: ±150ps
- Jitter (peak-to-peak) at 133MHz and 166MHz: ±75ps
- Spread spectrum compatible
- · Operating Frequency:
 - Std: 25MHz to 140MHz
 - A: 25MHz to 167MHz
- · Available in TSSOP package
- Use replacement part 87952AYI-147LF

DESCRIPTION:

The IDT5V2528 is a high performance, low-skew, low-jitter, phase-lock loop (PLL) clock driver. It uses a PLL to precisely align, in both frequency and phase, the feedback (FBOUT) output to the clock (CLK) input signal. The IDT5V2528 inputs,

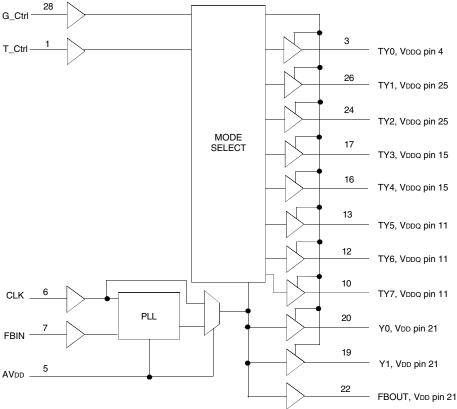
PLL core, Y0, Y1, and FBout buffers operate from the 3.3V Vdd and AVdd power supply pins.

One bank of ten outputs provide low-skew, low-jitter copies of CLK. Of the ten outputs, up to seven may be configured for 2.5V or 3.3V LVTTL outputs. The number of 2.5V outputs is controlled by 3-level input signals $G_{\rm C}$ trl and $T_{\rm C}$ trl, and by connecting the appropriate VDDQ pins to 2.5V or 3.3V. The 3-level input signals may be hard-wired to high-mid-low levels. Output signal duty cycles are adjusted to 50 percent, independent of the duty cycle at CLK. The outputs can be enabled or disabled via the $G_{\rm C}$ trl input. When the $G_{\rm C}$ trl input is mid or high, the outputs switch in phase and frequency with CLK; when the $G_{\rm C}$ trl is low, all outputs (except FBout) are disabled to the logic-low state.

Unlike many products containing PLLs, the IDT5V2528 does not require external RC networks. The loop filter for the PLL is included on-chip, minimizing component count, board space, and cost.

Because it is based on PLL circuitry, the IDT5V2528 requires a stabilization time to achieve phase lock of the feedback signal to the reference signal. This stabilization time is required, following power up and application of a fixed-frequency, fixed-phase signal at CLK, as well as following any changes to the PLL reference or feedback signals. The PLL can be bypassed for test purposes by strapping AVDD to ground.

FUNCTIONAL BLOCK DIAGRAM

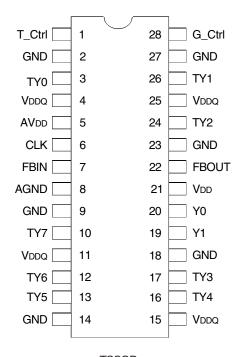


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INDUSTRIAL TEMPERATURE RANGE

MAY 2013

PIN CONFIGURATION



TSSOP TOP VIEW

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

	1017 17 17 17 17 17 17 17 17 17 17 17 17 1		
Symbol	Rating	Max.	Unit
VDD, VDDQ, AVDD	Supply Voltage Range	-0.5 to +4.6	V
VI (2)	Input Voltage Range	-0.5 to +5.5	V
Vo ⁽²⁾	Voltage Range applied to any	-0.5 to	V
	output in the HIGH or LOW state	VDD+0.5	
IIK (VI < 0)	Input Clamp Current	- 50	mA
Іок	Output Clamp Current	±50	mA
(VO < 0 or VO > VDD)			
lo	Continuous Output Current	±50	mA
(VO = 0 to VDD)			
VDD or GND	Continuous Current	±200	mA
Тѕтс	Storage Temperature Range	-65 to +150	°C
TJ	Junction Temperature	+150	°C

NOTES:

- 1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

CAPACITANCE(1)

Symbol	Description	Min	Тур.	Max.	Unit	
CIN	Input Capacitance		_	5	_	рF
	VI = VDD or GND					
Co	Output Capacitano	_	6	_	рF	
	VI = VDD or GND					
CL	Load Capacitance	2.5V outputs	_	20	_	рF
		3.3V outputs	_	30	_	

NOTE:

1. Unused inputs must be held HIGH or LOW to prevent them from floating.

RECOMMENDED OPERATING RANGE

Symbol	Description		Min.	Тур.	Max.	Unit
VDD, AVDD (1)	Power Supply Voltage		3	3.3	3.6	V
V _{DDQ} ⁽¹⁾	Power Supply Voltage	2.5V Outputs	2.3	2.5	2.7	V
		3.3V Outputs	3	3.3	3.6	
TA	Ambient Operating Temperature		-40	+25	+85	°C

NOTE:

1. All power supplies should operate in tandem. If VDD or VDDD is at a maximum, then VDDD or VDD (respectively) should be at maximum, and vice-versa.

PIN DESCRIPTION

Terminal			
Name	No.	Туре	Description
CLK ⁽¹⁾	6	1	Clock input
FBIN	7	1	Feedbackinput
G_Ctrl ⁽²⁾	28	3-level	$3-levelinputfor2.5V/3.3VOutputSelect/Outputbankenable.WhenG_CtrlisLOW, alloutputsexceptFBOUTaredisabled$
			to a logic-LOW state. When G_Ctrl is MID or HIGH, all outputs are enabled and switch at the same frequency as CLK (see
			OUTPUT SELECTION table).
T_Ctrl ⁽²⁾	1	3-level	3-level input for 2.5V / 3.3V Output Select (see OUTPUT SELECTION table)
FBOUT	22	0	Feedbackoutput
TY (7:0)	3, 10, 12, 13,	0	2.5V or 3.3V Clock outputs. 1, 2, 3, 5, or 7 of these outputs may be selected as 2.5V outputs (see OUTPUT SELECTION table).
	16, 17, 24, 26		
Y (1:0)	19,20	0	3.3V Clock Outputs
AV _{DD} ⁽³⁾	5	Power	3.3V Analog power supply. AVDD provides the power reference for the analog circuitry.
AGND	8	Ground	Analog ground. AGND provides the ground reference for the analog circuitry.
VDD	21	Power	3.3V Power supply
VDDQ	4, 11, 15, 25	Power	2.5V or 3.3V Power supply for TY outputs
GND	2, 9, 14, 18	Ground	Ground
	23,27		

NOTES

- 1. CLK must have a fixed frequency and fixed phase for the PLL to obtain phase lock. Once the circuit is powered up and a valid CLK signal is applied, a stabilization time of 1ms is required for the PLL to phase lock the feedback signal to the reference signal.
- 2. 3-level inputs will float to MID logic level if left unconnected.
- 3. AVDD can be used to bypass the PLL for test purposes. When AVDD is strapped to ground, PLL is bypassed and CLK is buffered directly to the outputs.

STATIC FUNCTION TABLE (AVDD = 0V) (1)

Inputs			Outputs			
G_Ctrl	T_Ctrl	CLK	TY(7:0)	Y(1:0)	FBOUT	
L	Х	L	L	L	L	
L	Х	Ι	L	L	Н	
se	e	Н	Н	Н	Н	
OUTPUT SELECTION		L	L	L	L	
table		running	running	running	running	

NOTE:

 AVDD should be powered up along with VDD, before setting AVDD to ground, to put the control pins in a valid state.

OUTPUT SELECTION

			VDDQ
G_Ctrl	T_Ctrl	TY(7:0)	Configuration
М	L	TY ₀ (2.5V)	Pin 4 (2.5V)
		TY1 - TY7 (3.3V)	Pins 11, 15, 25 (3.3V)
М	М	TY1,TY2(2.5V)	Pin 25 (2.5V)
		TY0, TY3 - TY7 (3.3V)	Pins 4, 11, 15 (3.3V)
М	Н	TY0-TY2(2.5V)	Pins 4, 25 (2.5V)
		TY3 - TY7 (3.3V)	Pins 11, 15 (3.3V)
Н	L	TY0-TY4 (2.5V)	Pins 4, 15, 25 (2.5V)
		TY5 - TY7 (3.3V)	Pin 11 (3.3V)
Н	М	TY1 - TY7 (2.5V)	Pins 11, 15, 25 (2.5V)
		TY ₀ (3.3V)	Pin 4 (3.3V)
Н	Н	TY ₀ - TY ₇ (3.3V)	Pins 4, 11, 15, 25 (3.3V)

DYNAMIC FUNCTION TABLE (AVDD = 3.3V)

Inputs			Outputs			
G_Ctrl	T_Ctrl	CLK	TY(7:0)	Y(1:0)	FBOUT	
L	Х	L	L	L	L	
L	Х	Н	L	L	Н	
see OL	see OUTPUT		L	L	L	
SELECTION table		Н	Н	Н	Н	

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Symbol	Parameter		Test Conditions	Min.	Typ. ⁽¹⁾	Max	Unit
Vıĸ	Input Clamp Voltage	Iı = -18mA				- 1.2	٧
VIH	Input HIGH Level	CLK, FBIN		2			V
VIL	Input LOW Level	CLK, FBIN				0.8	٧
Vінн	Input HIGH Voltage Level(2)	3-Level Inputs Only		VDD - 0.6			V
Vimm	Input MID Voltage Level(2)	3-Level Inputs Only		V _{DD} /2 - 0.3		$V_{DD}/2 + 0.3$	V
VILL	Input LOW Voltage Level(2)	3-Level Inputs Only				0.6	V
Vон	Output HIGH Voltage Level	Іон = -100μΑ		V _{DD} - 0.2			V
	(3.3V Outputs)	Iон = -12mA		2.4			ĺ
Vон	Output HIGH Voltage Level	Іон = -100μΑ		Vpp - 0.1			
	(2.5V Outputs)	Iон = -12mA		2			٧
Vol	Output LOW Voltage Level	IoL = 100μA				0.2	٧
	(3.3V Outputs)	IoL = 12mA				0.4	
Vol	Output LOW Voltage Level	IoL = 100μA				0.1	٧
	(2.5V Outputs)	IoL = 12mA				0.4	ĺ
l3	3-Level Input DC Current	VIN = VDD	HIGH Level			+200	
	(G_Ctrl, T_Ctrl)	VIN = VDD/2	MID Level	-50		+50	μΑ
		Vin = GND	LOW Level	-200			
lı	Input Current	VI = VDD or GND	·			±5	μΑ

NOTES:

- 1. For conditions shown as Min or Max, use the appropriate value specified under recommended operating conditions.
- 2. These inputs are normally wired to VDD, GND, or left floating. Internal termination resistors bias floating inputs to VDD/2. If these inputs are switched, the function and timing of the outputs may be glitched, and the PLL may require an additional tLOCK time before all datasheet limits are achieved.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions	Typ. ⁽¹⁾	Max	Unit
IDDPD	Power Down Supply Current	$V_{DD} = 3.6, V_{DDQ} = 2.7V / 3.3V, AV_{DD} = 0V$	8	40	μΑ
Idda	AVDD Supply Current	$V_{DD} = AV_{DD} = 3.6V$, $V_{DDQ} = 2.7V / 3.3V$, $CLK = 0$ or V_{DD}	3.5	10	mA
IDD	Dynamic Power Supply Current	$V_{DD} = AV_{DD} = 3.6V$, $V_{DDQ} = 2.7V / 3.3V$, $C_L = 0pF$	500	_	μA/MHz
lodd	Dynamic Power Supply	$V_{DD} = AV_{DD} = V_{DDQ} = 3.6V$ $C_L = 30pF, CLK = 100MHz$	15	_	mA
	Current per Output	V _{DD} = AV _{DD} = 3.6V, V _{DDQ} = 2.7V C _L = 20pF, C _L K = 100MHz	12	_	

NOTE:

1. For nominal voltage and temperature.

INPUT TIMING REQUIREMENTS OVER OPERATING RANGE

		5V2528		5V2528A		
		Min	Max	Min	Max	Units
fcLock	Clockfrequency	25	140	25	167	MHz
	Input clock duty cycle	40%	60%	40%	60%	
tlock	Stabilization time ⁽¹⁾	_	1		1	ms

NOTE:

SWITCHING CHARACTERISTICS OVER OPERATING RANGE - 5V2528(1)

Symbol	Parameter ⁽²⁾	Min.	Тур.	Max.	Unit
tphase error	Phase Error from Rising Edge CLK to Rising Edge FBIN (100MHz-133MHz)	— 150	_	150	ps
tphase error - jitter ⁽³⁾	Phase Error minus Jitter from Rising Edge CLK to Rising Edge FBIN (133MHz)	 50	_	50	ps
tsk1(0) ⁽⁴⁾	Output Skew between 3.3V Outputs	_	_	150	ps
tsk2(0) ⁽⁴⁾	Output Skew between 2.5V Outputs	_	_	150	ps
tsk3(0) ^(4,5)	Output Skew between 2.5V and 3.3V Outputs	_	_	200	ps
tJ	Cycle-to-Cycle Output Jitter (Peak-to-Peak) at 133MHz	- 75	_	75	ps
	Duty Cycle	45	_	55	%
tR	Output Rise Time for 3.3V Outputs (20% to 80%)	0.8	_	2.1	ns
t=	Output Fall Time for 3.3V Outputs (20% to 80%)	0.8	_	2.1	ns
tR	Output Rise Time for 2.5V Outputs (20% to 80%)	0.5	_	1.5	ns
tF	Output Fall Time for 2.5V Outputs (20% to 80%)	0.5	_	1.5	ns

SWITCHING CHARACTERISTICS OVER OPERATING RANGE - 5V2528A(1)

Symbol	Parameter ⁽²⁾		Min.	Тур.	Max.	Unit
tphase error	Phase Error from Rising Edge CLK to Rising E	dge FBIN (100MHz-166MHz)	-150		150	ps
tphase error - jitter ⁽³⁾	Phase Error minus Jitter from Rising Edge CLk	(to Rising Edge FBIN (166MHz)	 50		50	ps
tsk1(0) ⁽⁴⁾	Output Skew between 3.3V Outputs		_		150	ps
tsk2(0) ⁽⁴⁾	Output Skew between 2.5V Outputs		_		150	ps
tsk3(0) ^(4,5)	Output Skew between 2.5V and 3.3V Outputs	25MHz to 133MHz	_		200	ps
		133MHz to 166MHz	_		250	
tı	Cycle-to-Cycle Output Jitter (Peak-to-Peak) at	166MHz	 75	_	75	ps
	Duty Cycle		45		55	%
tr	Output Rise Time for 3.3V Outputs (20% to 80%)	%)	0.8		2.1	ns
t⊨	Output Fall Time for 3.3V Outputs (20% to 80%)	0.8		2.1	ns
tr	Output Rise Time for 2.5V Outputs (20% to 80%)		0.5	_	1.5	ns
tF	Output Fall Time for 2.5V Outputs (20% to 80%)	0.5	_	1.5	ns

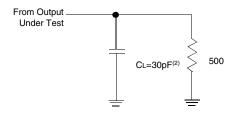
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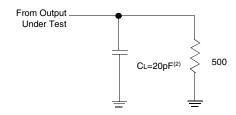
- 1. All parameters are measured with the following load conditions: $30pF \parallel 500\Omega$ for 3.3V outputs and $20pF \parallel 500\Omega$ for 2.5V outputs.
- 2. The specifications for parameters in this table are applicable only after any appropriate stabilization time has elapsed.
- 3. Phase error does not include jitter.
- 4. All skew parameters are only valid for equal loading of all outputs.
- 5. Measured for VDDQ = 2.3V and 3V, 2.5V and 3.3V, or 2.7V and 3.6V.

^{1.} Time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal. For phase lock to be obtained, a fixed-frequency, fixed-phase reference signal must be present at CLK. Until phase lock is obtained, the specifications for propagation delay, skew, and jitter parameters given in the switching characteristics table are not applicable.

.5 / 3.3V PHASE-LOCK LOOP CLOCK DRIVER

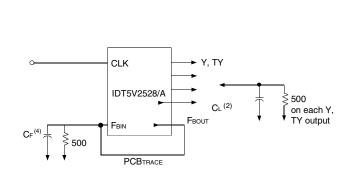
TEST CIRCUIT AND VOLTAGE WAVEFORMS

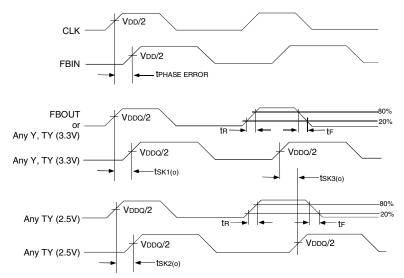




Test Circuit for 3.3V Outputs

Test Circuit for 2.5V Outputs



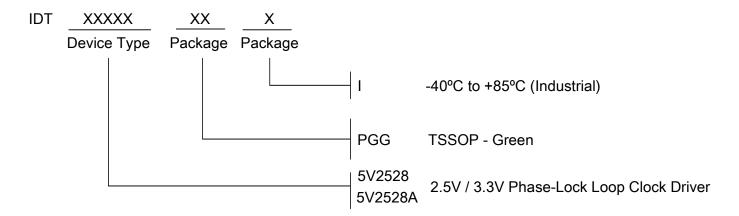


PHASE ERROR AND SKEW CALCULATIONS(3,4)

NOTES:

- 1. All inputs pulses are supplied by generators having the following characteristics: PRR \leq 100MHz Zo = 50Ω , tR \leq 1.2 ns, tF \leq 1.2 ns.
- 2. CL includes probe and jig capacitance.
- ${\tt 3.}$ The outputs are measured one at a time with one transition per measurement.
- 4. Phase error measurements require equal loading at outputs Y, TY, and FBoUT. $C_F = C_L C_{FBIN} C_{PCBITace}$; $C_{FBIN} \cong 5pF$.

ORDERING INFORMATION



REVISION HISTORY

Rev	Table	Page	Discription of Change	Date
А		1	NRND - Not Recommended for New Designs	5/16/13
А		1	Product Discontinuation Notice - Last Time Buy Expires on October 28, 2014, PDN# CQ-13-02	12/3/13

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